

| | | | | |
|-----------------------------------|--|---------------------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. 10/686,898 | Applicant(s)/Patent Under Reexamination SENZAKI, YOSHIHIDE | |
| | | Examiner B. Chen | Art Unit 1762 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-4,997,722 | 03-1991 | Adler, Edward | 428/596 |
| | B | US-4,997,516 | 03-1991 | Adler, Edward | 216/101 |
| | C | US-5,753,309 | 05-1998 | Fakler et al. | 427/399 |
| | D | US-5,925,403 | 07-1999 | Yoshizawa et al. | 427/126.3 |
| | E | US-6,482,740 | 11-2002 | Soininen et al. | 438/686 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.